



The effect of Tfx on ERL using a measured test fixture

April 13th 2021

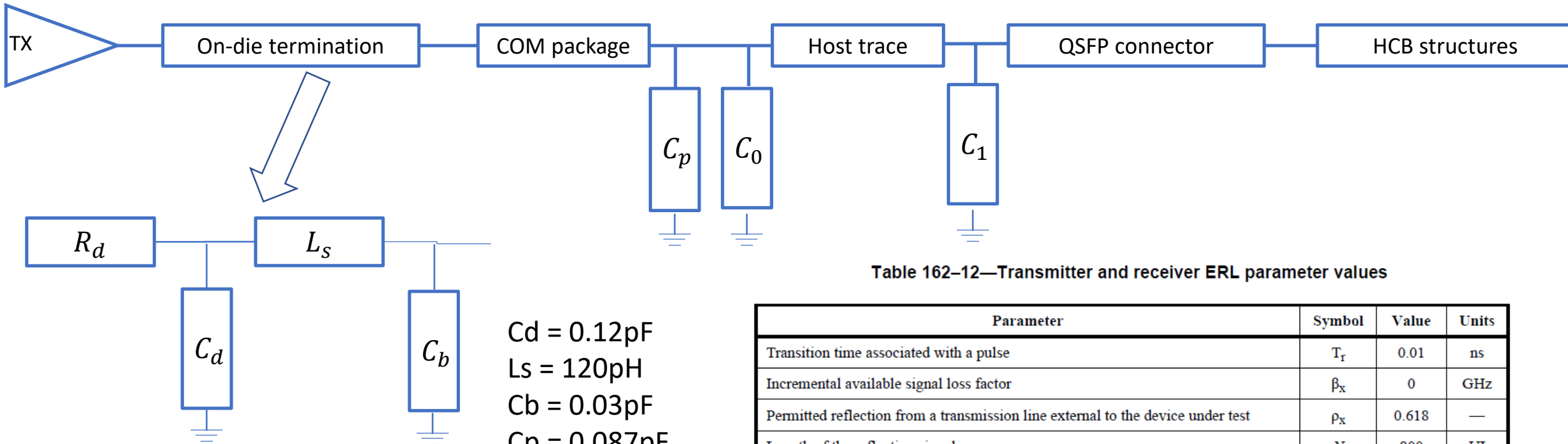
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Tao Hu Marvell

Introduction

- The purpose of having the Time-Gated propagation Delay (T_{fx}) in the ERL measurement is to remove the effect of the discontinuity caused by the RF connector of the test fixture.
- This presentation shows the results of simulations to determine the effect of T_{fx} value on the measurement of ERL.
- The simulations are of the CR, copper cable host but it is expected that the results will be applicable to all ERL measurements.
- Based on this work I intend to write a comment to change the value of T_{fx} for these measurements from 0.2ns to 0.3ns.

ERL simulation block diagram at TP2



$C_d = 0.12\text{pF}$
 $L_s = 120\text{pH}$
 $C_b = 0.03\text{pF}$
 $C_p = 0.087\text{pF}$
 $C_0 = 0.029\text{pF}$
 $C_1 = 0.019\text{pF}$

Tfx: 0 to .5ns

Host trace length: 1mm to 400mm w/step 1mm

Host trace impedance: 100 OHM

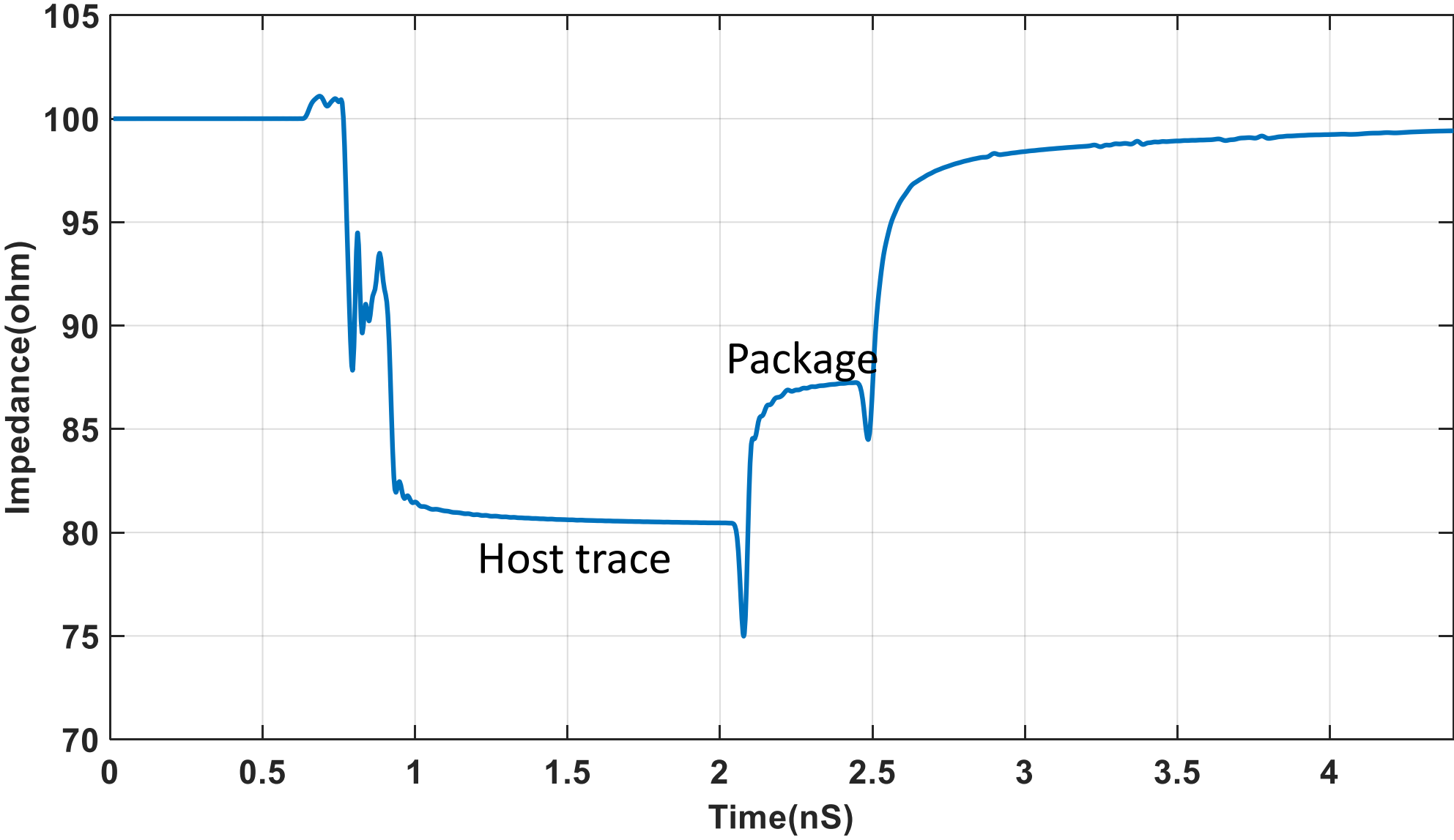
Package length: 12mm

Table 162-12—Transmitter and receiver ERL parameter values

Parameter	Symbol	Value	Units
Transition time associated with a pulse	T_r	0.01	ns
Incremental available signal loss factor	β_x	0	GHz
Permitted reflection from a transmission line external to the device under test	ρ_x	0.618	—
Length of the reflection signal	N	800	UI
Equalizer length associated with reflection signal	N_{bx}	0	UI
Time-gated propagation delay	T_{fx}	0.2	ns
Tukey window flag	tw	1	—

HCB as perfect 100OHM 2.5dB loss PCB

TDR of package, host trace, connector and perfect 100OHM PCB

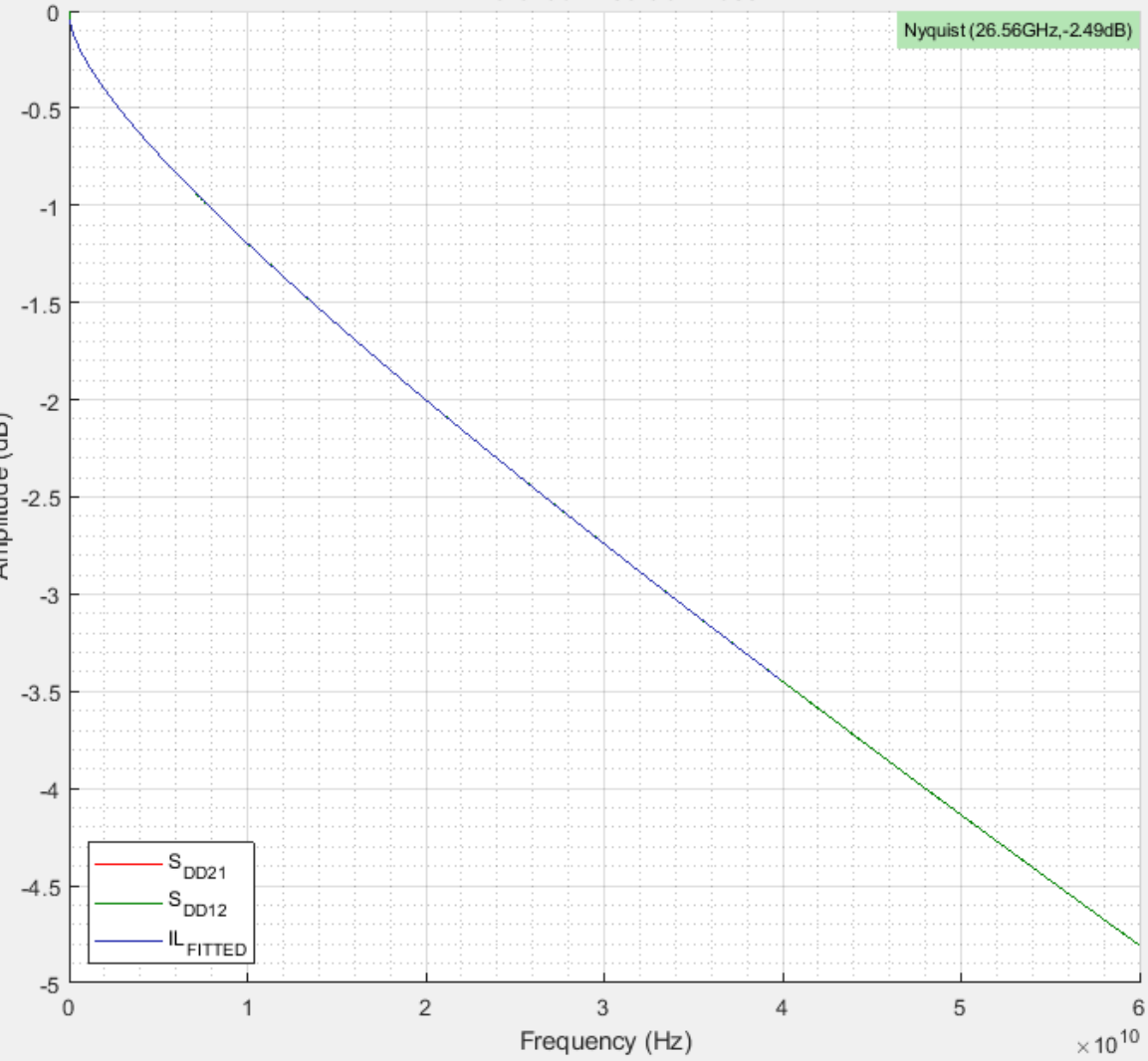


Perfect 100OHM PCB S parameter

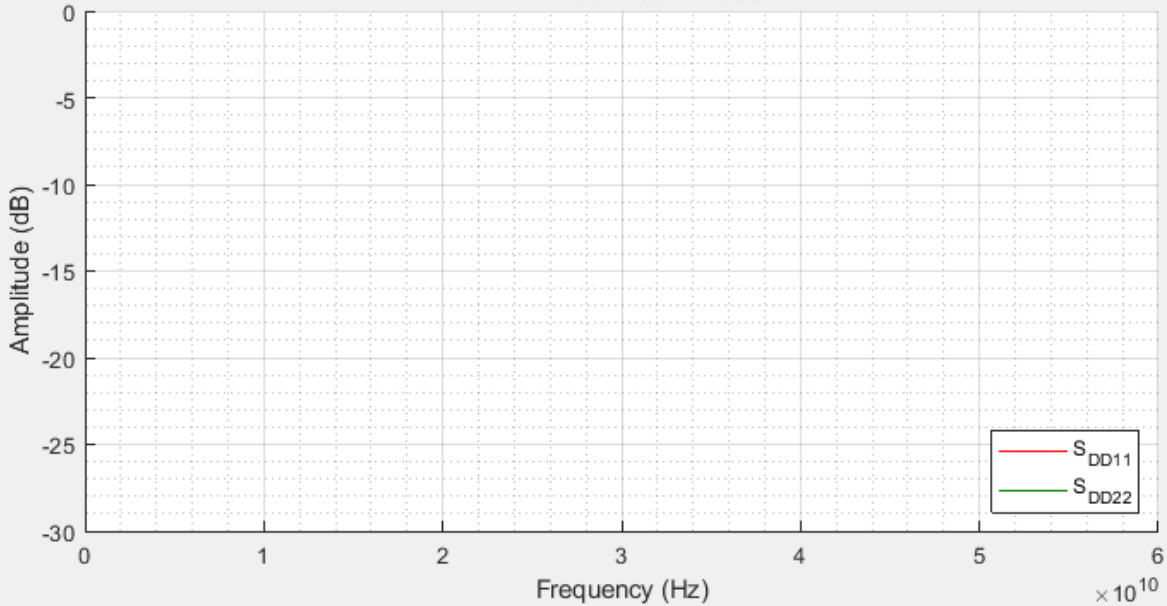
Diff Port Reference: 1 and 3
 Channel Spec: ILD - 802.3 Test
 Baud Rate Gsym/sec: 53.125

 Touchstone File Name: 100OHM_2P5dB_63P5mm.s4p

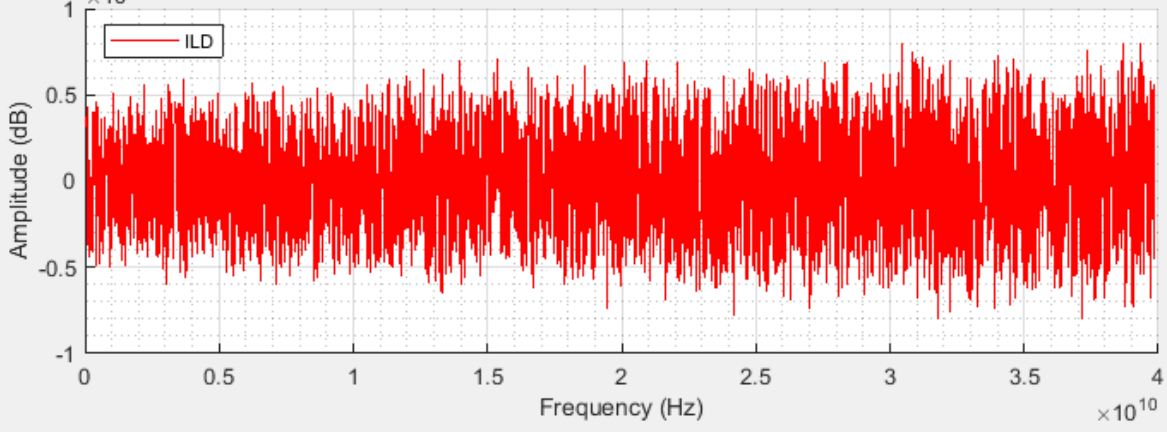
Differential Insertion Loss



Differential Return Loss



Insertion Loss Deviation



Port Assign

Port 1: 1

Port 2: 2

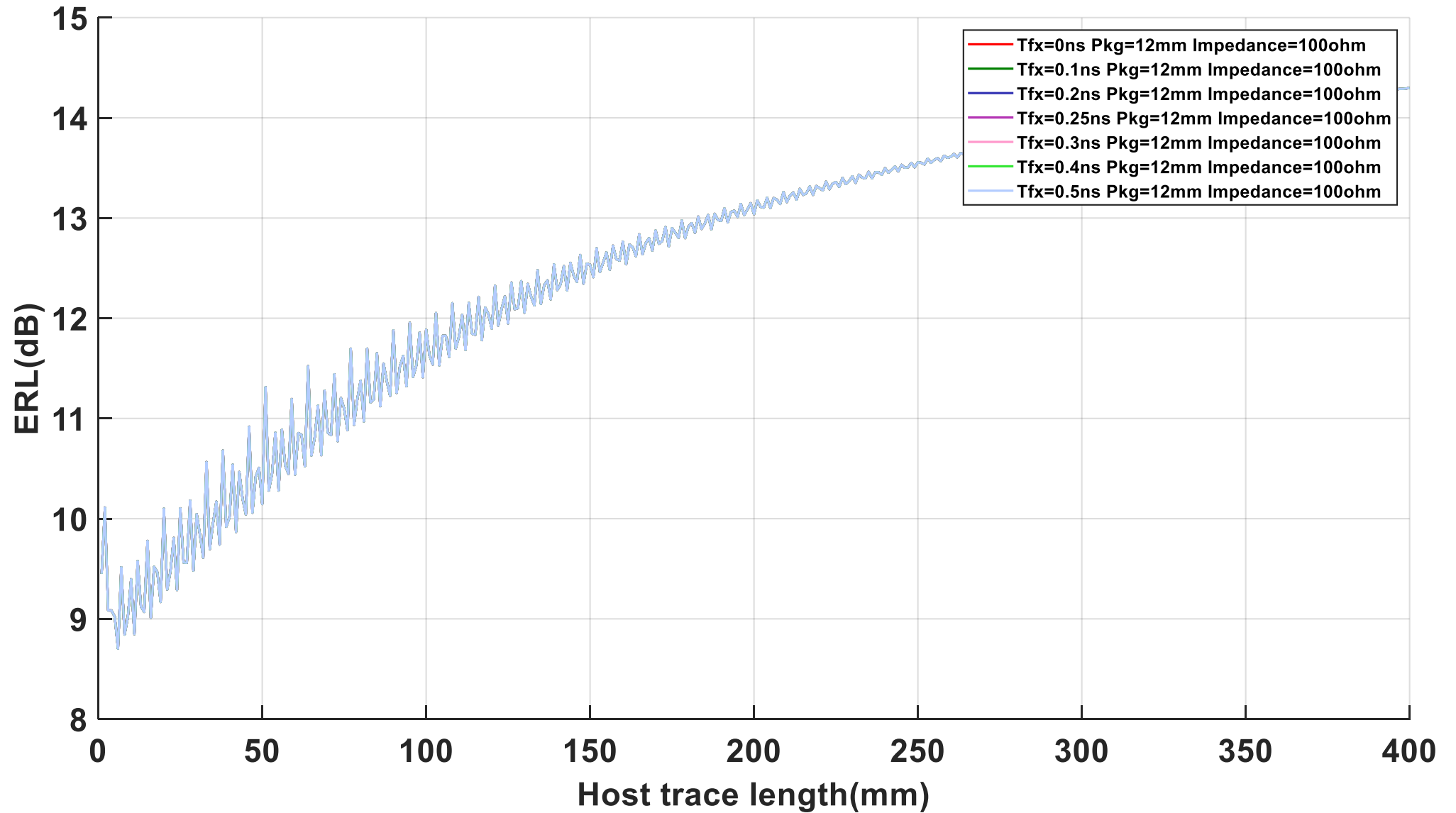
Port 3: 3

Port 4: 4

ILD Coeff

a0	-0.000	dB
a1	1.536	dB $\times 10^{-2}$
a2	0.211	dB/GH $\times 10^{-2}$
a3	2.810	dB
a4	0.053	dB/GH $\times 10^{-2}$
a5	0.000	dB
a6	0.000	dB/GH $\times 10^{-2}$
ILD RMS	0.000	

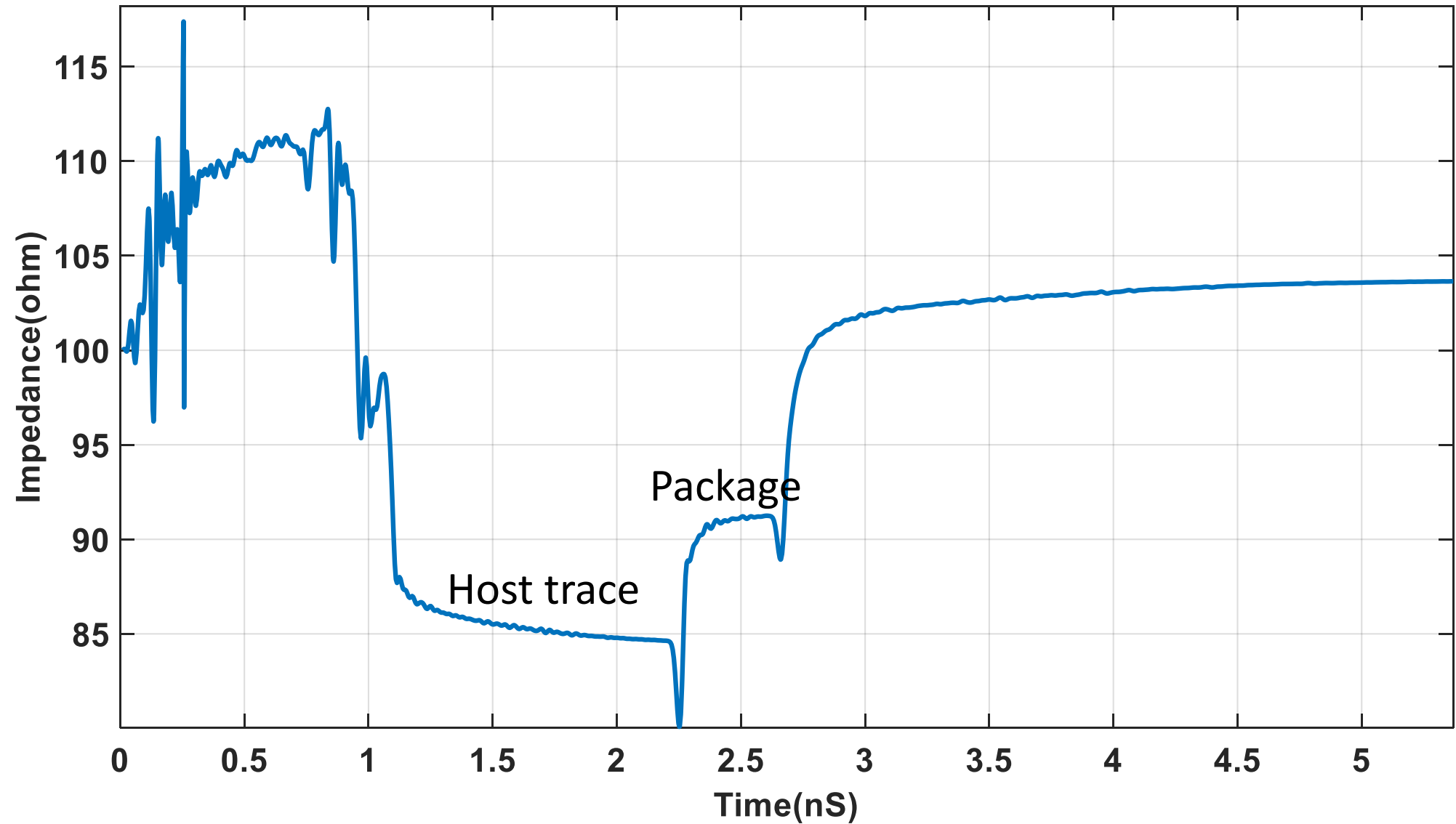
ERL with perfect 100 Ohm trace



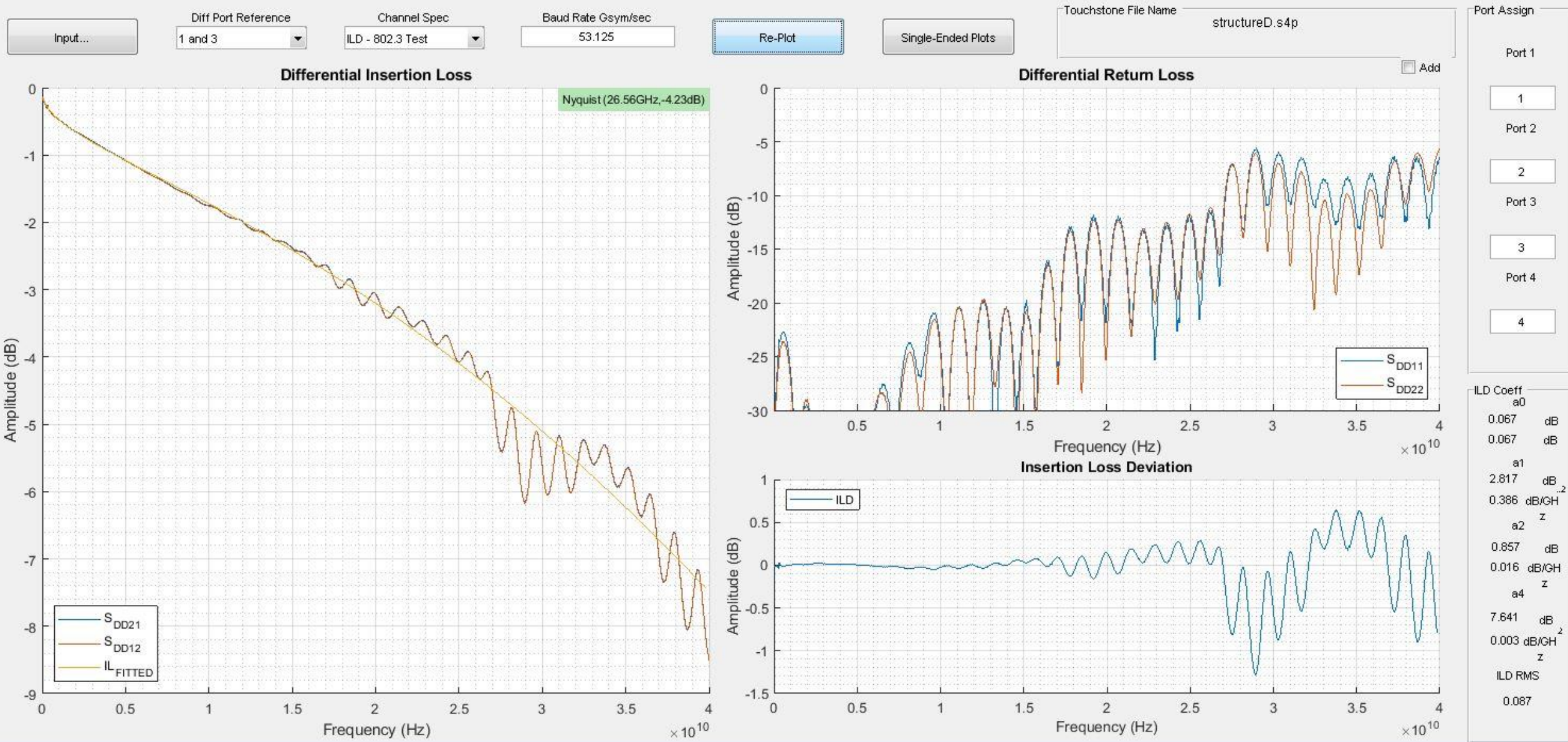
HCB as measured test trace Structure D

**Molex SMA 2.92mm(73252-0090) + M6 100 Ohm 2.26 inch Stripline +
Molex SMA 2.92mm(73252-0090)**

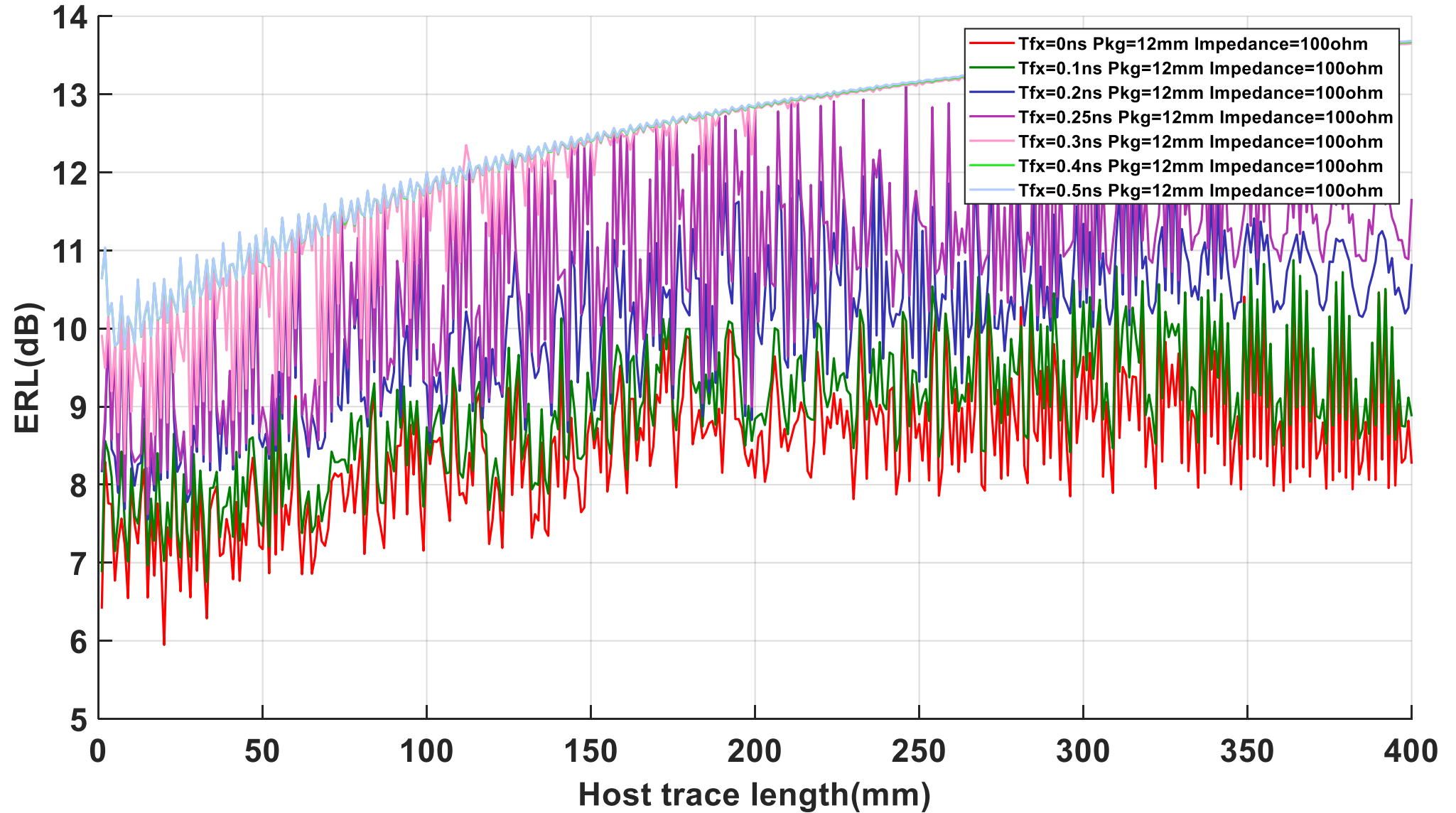
TDR of package, host trace, connector and structure D



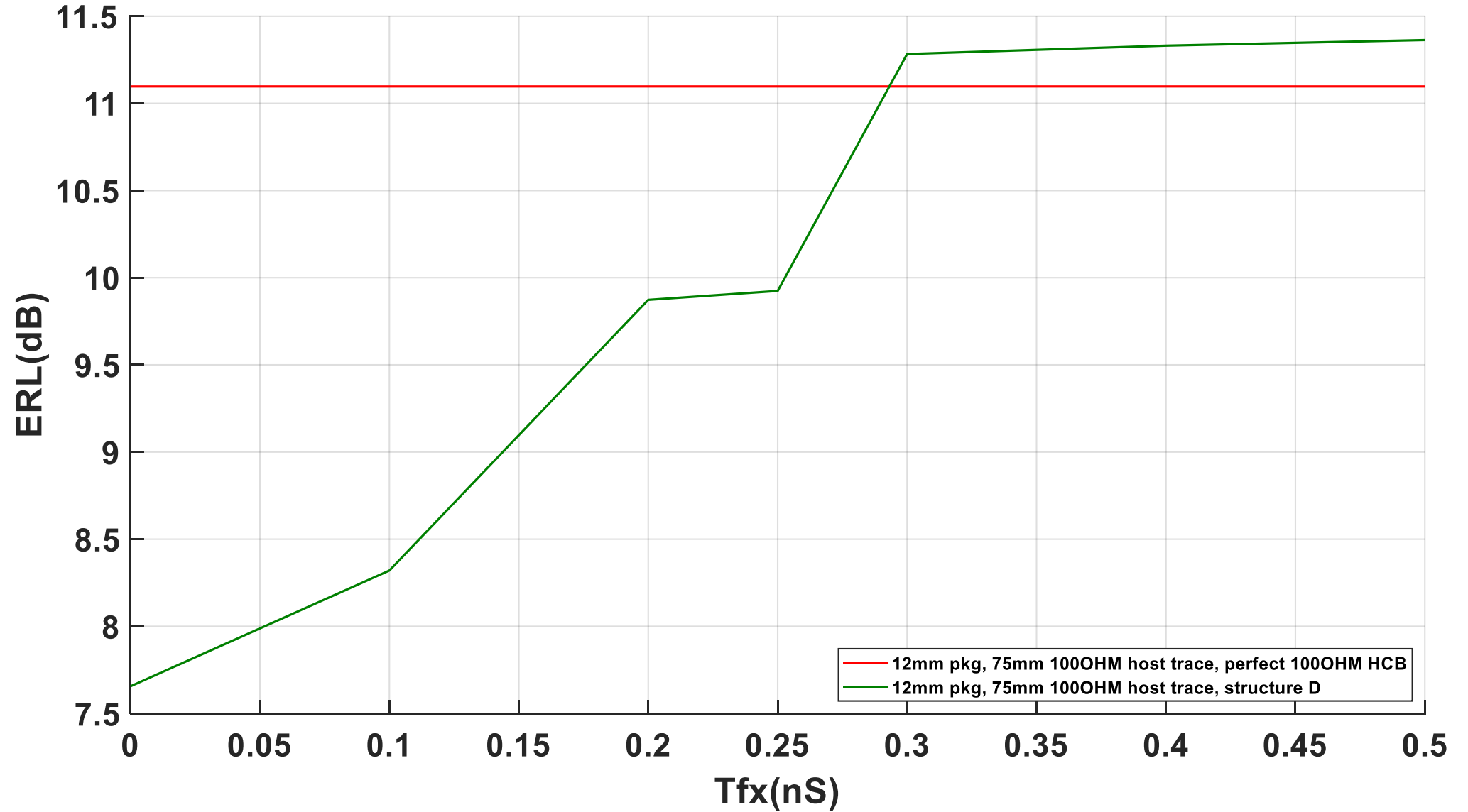
Structure D S parameter



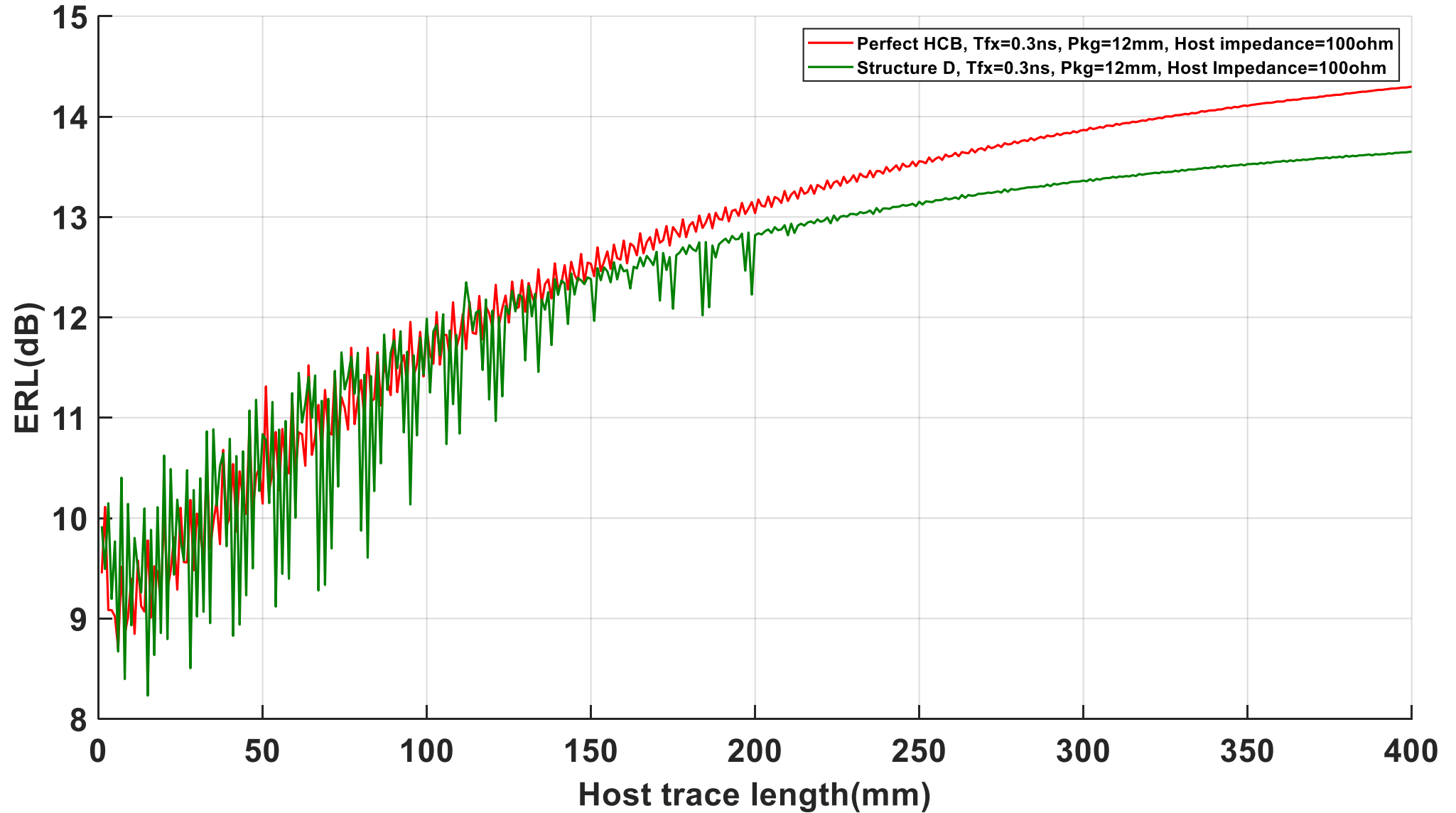
ERL with measured structure D



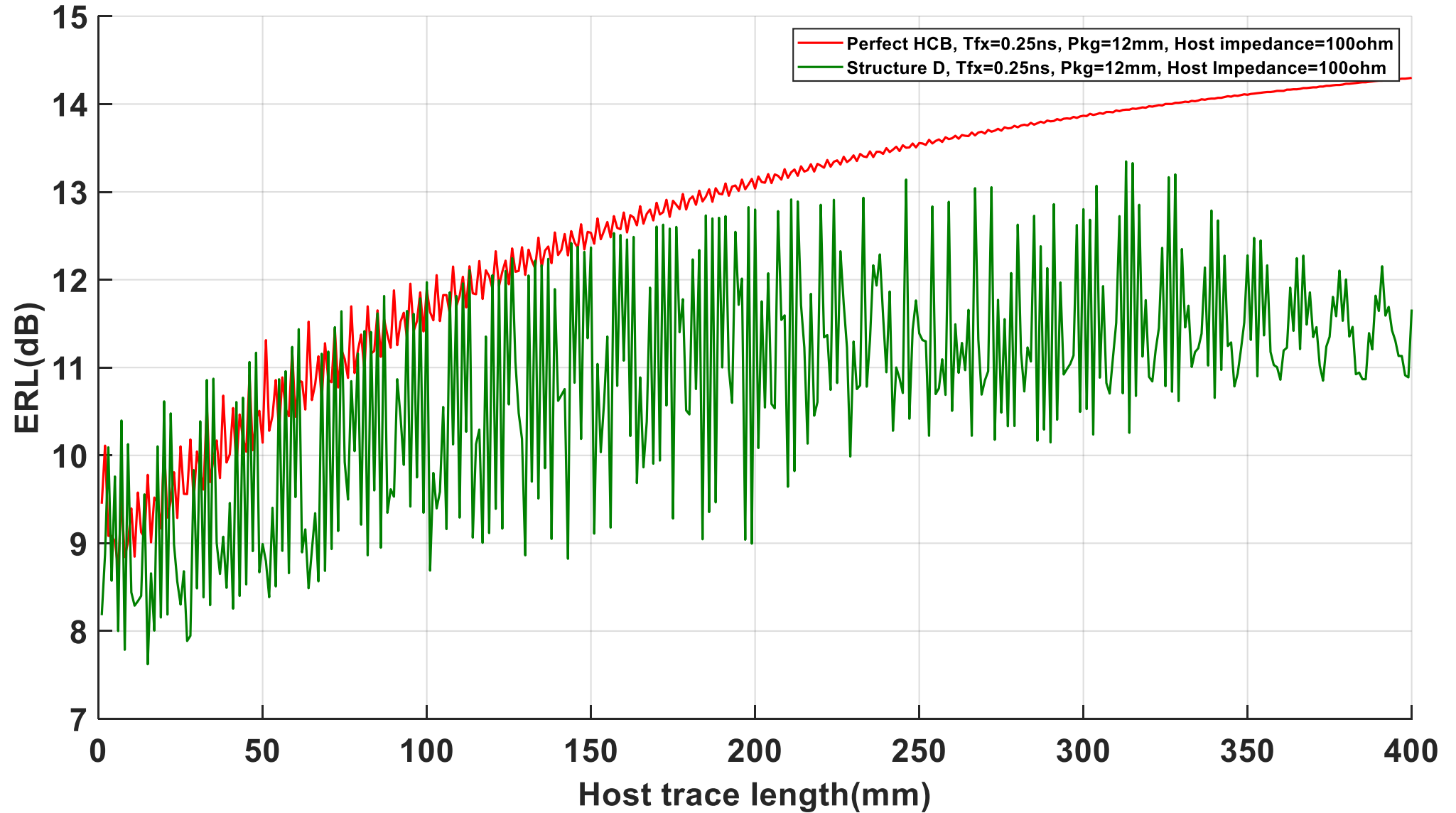
ERL versus Tfx



ERL versus host trace length when Tfx=0.3ns



ERL versus host trace length when Tfx=0.25ns



Conclusions

- The present value of 0.2ns for Tfx is too short to remove the effect of the RF connector resulting in pessimistic (and variable) ERL measurements.
- Having too large a value of Tfx can result in optimistic results as it may remove the effect of discontinuities in the host itself.
- A value of 0.3ns is large enough to remove the RF connector effects without affecting the measurements of the host itself.

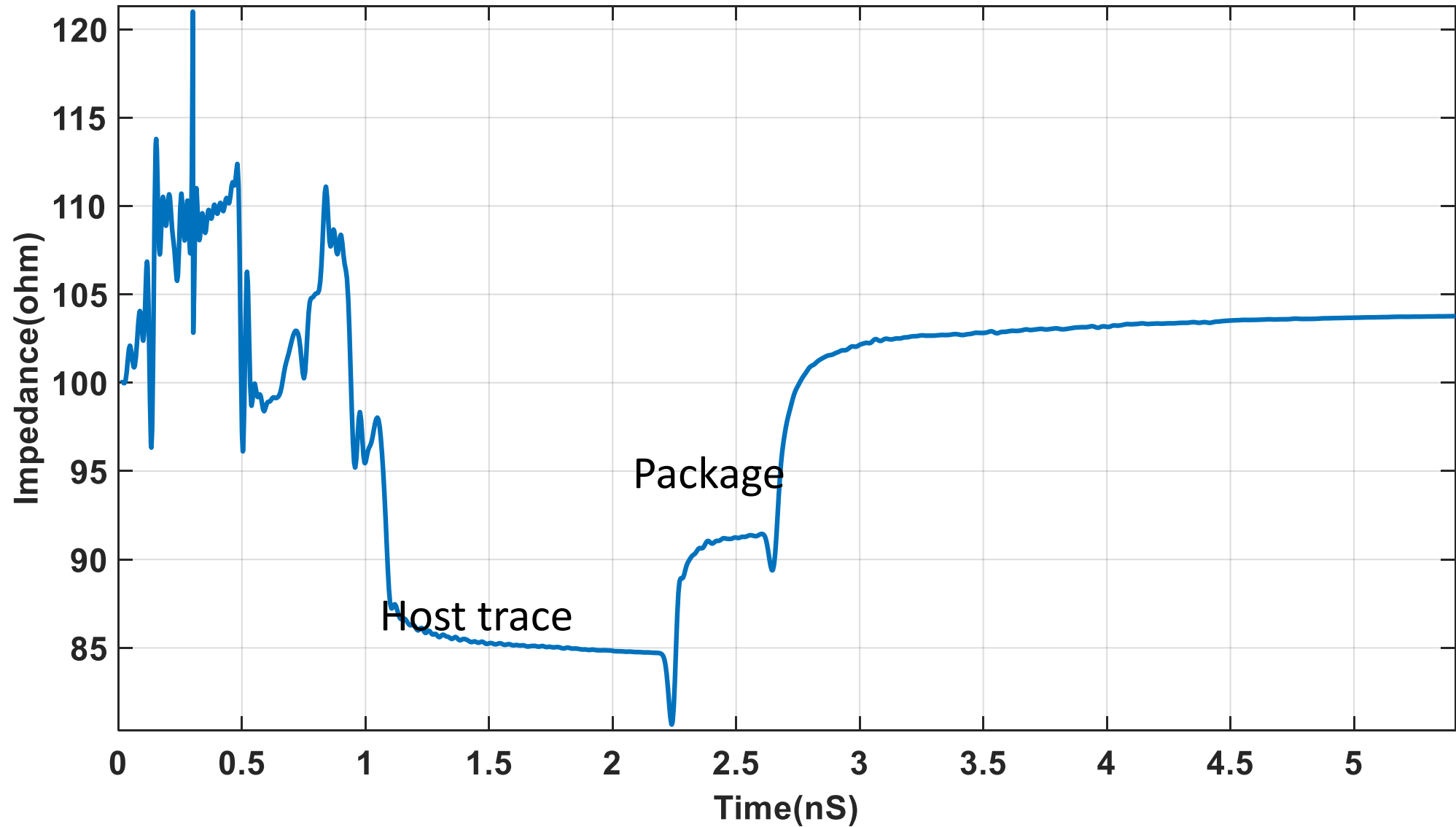
Backup

Effect of discontinuity in test trace.

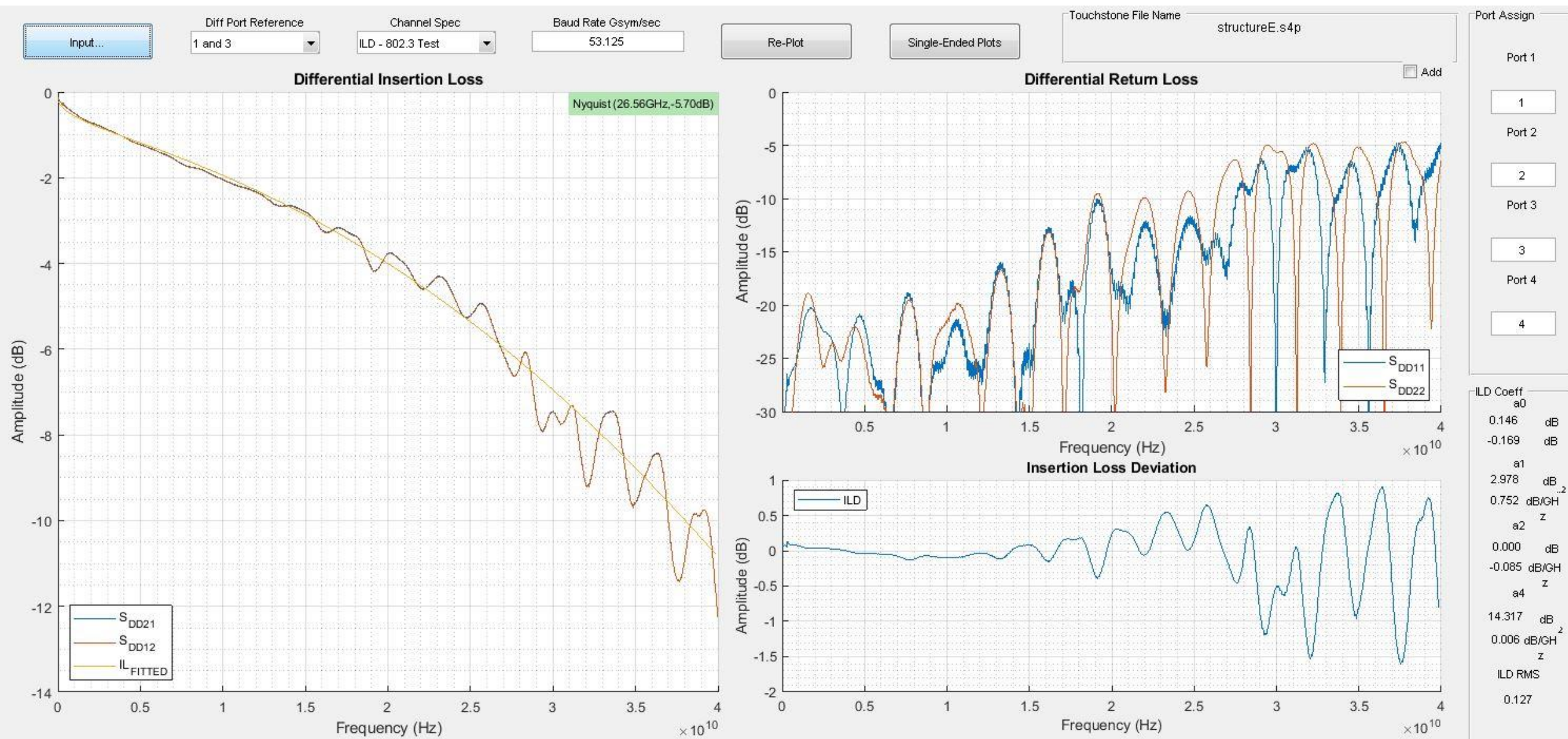
HCB as measured Structure E

**Molex SMA 2.92mm(73252-0090) +
M6 100 Ohm 1.13 inch Microstrip + Via +
M6 100 Ohm 1.13 inch Stripline +
Molex SMA 2.92mm(73252-0090)**

TDR of package, host trace, connector and structure E



Structure E S parameter



Port Assign

Port 1: 1

Port 2: 2

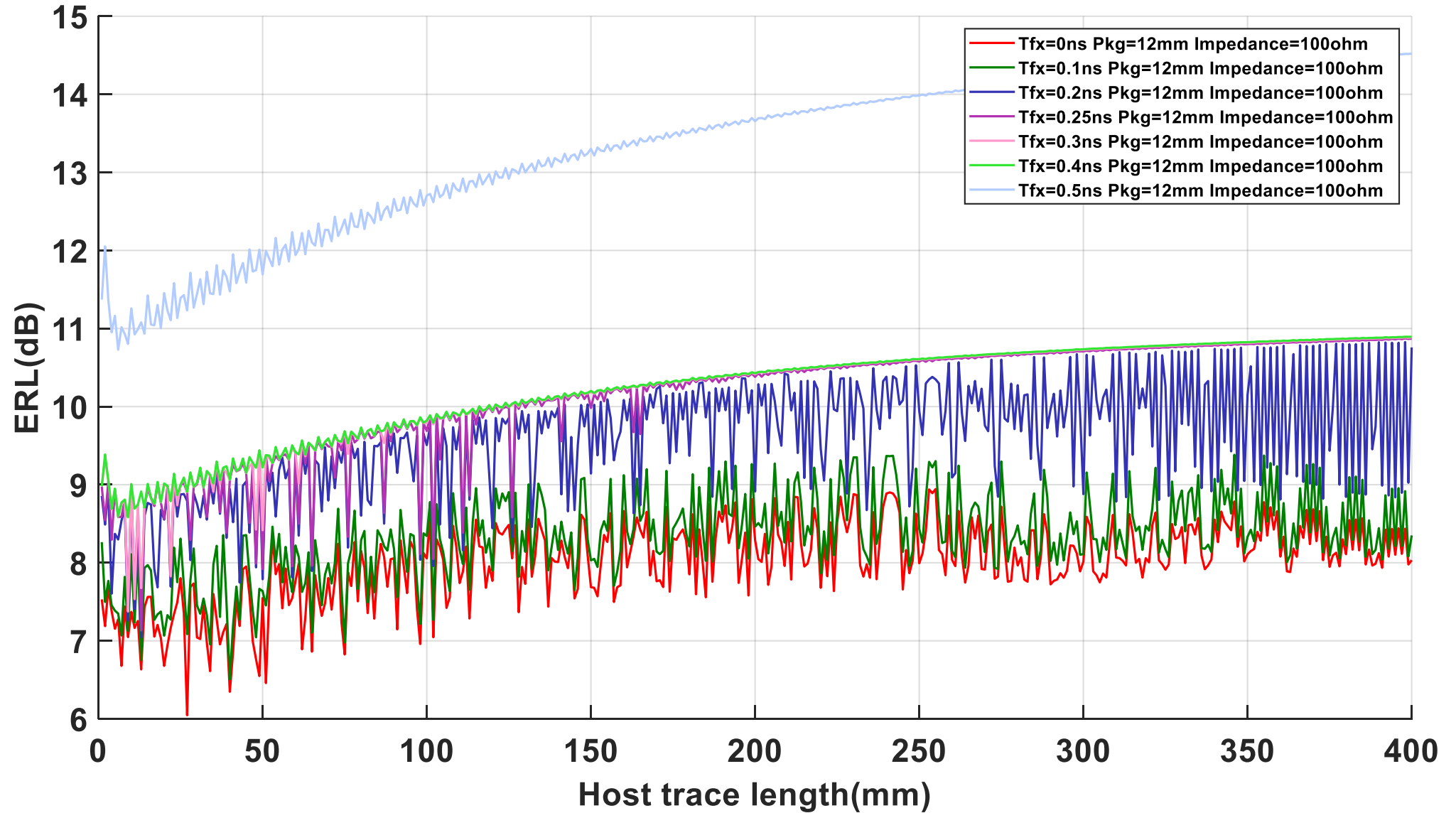
Port 3: 3

Port 4: 4

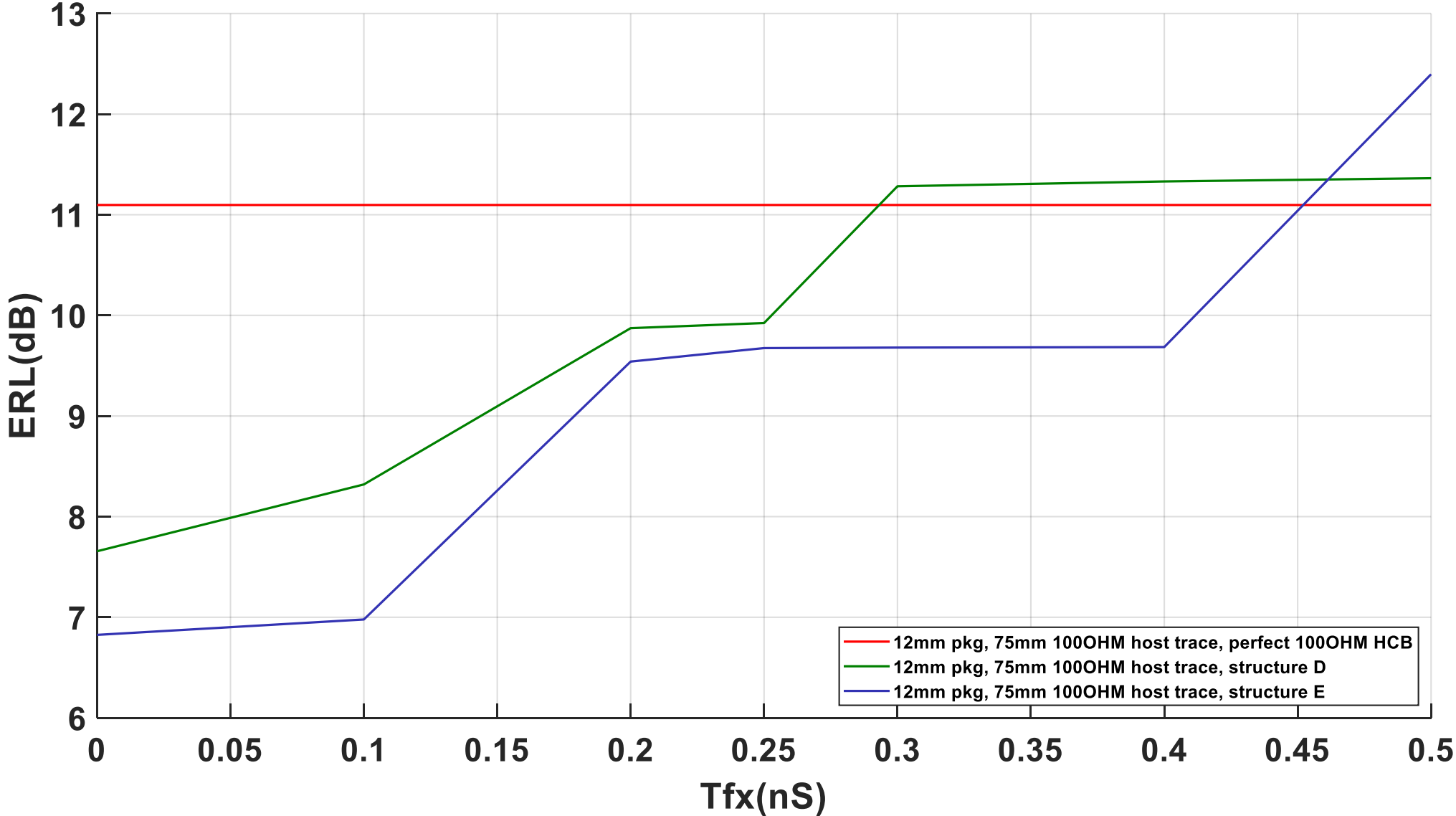
ILD Coeff

a0	0.146	dB
a1	2.978	dB
a2	0.752	dB/GH ²
a3	0.000	dB
a4	-0.085	dB/GH ²
a5	14.317	dB
a6	0.006	dB/GH ²
ILD RMS	0.127	

ERL with measured structure E



ERL versus Tfx



ERL with Tfx = 0.4ns

ERL versus host trace length when Tfx=0.4ns

